

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
10/790,879	MOCHIZUKI, HI	DEAKI
Examiner	Art Unit	
Ted M. Wang	2611	

SEARCHED						
Class	Subclass	Date	Examiner			
375	239, 357	5/21/2008	TW			
370	216, 506	5/21/2008	TW			
370	512	5/21/2008	TW			
340	512	5/21/2008	TW			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
375	239, 357	5/21/2008	TW		
340	512	5/21/2008	TW		
370	216, 506	5/21/2008	TW		
370/512		5/21/2008	TW		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	5/21/2008	TW		
ODP- Searched and reviewed from EAST and PALM	5/21/2008	TW		
Inventor search- Mochizuki with Hideaki	5/21/2008	TW		
IEEExplor - Adavnce - fram* pulse and mask* and (alarm or fault or fail*)	5/21/2008	TW		
IEEExplor - Author -Mochizuki Hideaki	5/21/2008	TW		